

FIG. 1D
(PRIOR ART)

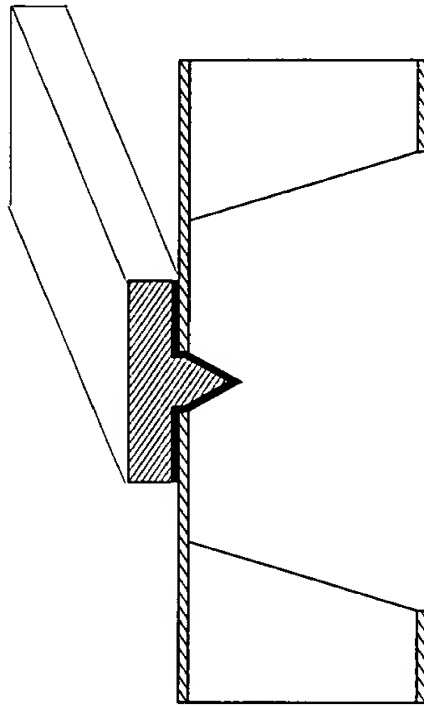


FIG. 1E
(PRIOR ART)

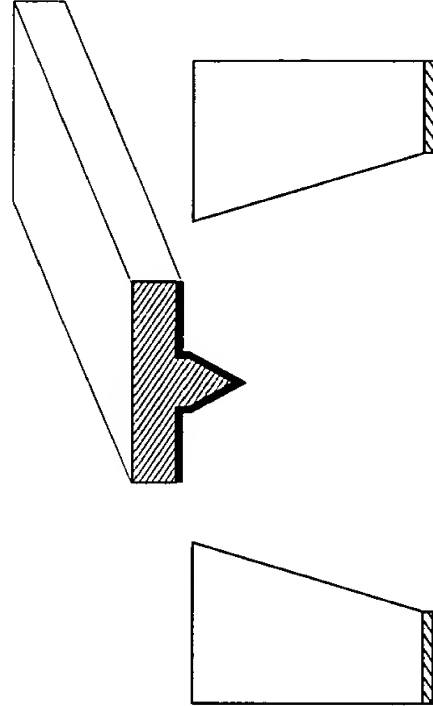


FIG. 1F
(PRIOR ART)

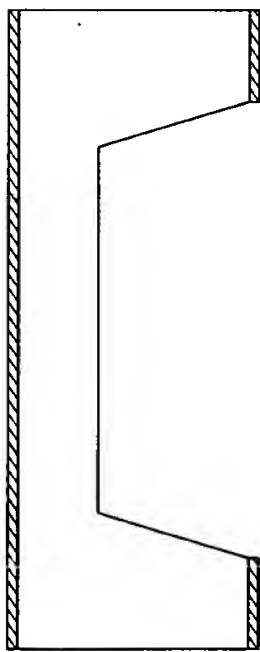


FIG. 1A
(PRIOR ART)

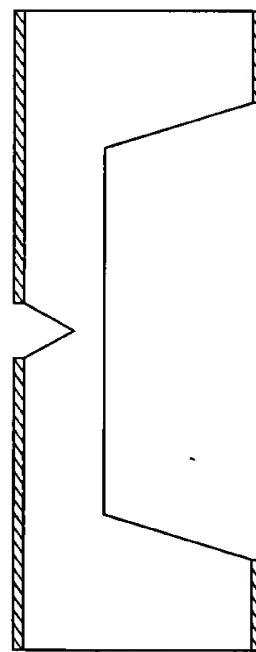


FIG. 1B
(PRIOR ART)

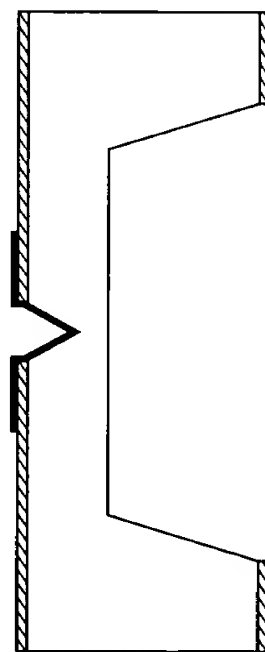


FIG. 1C
(PRIOR ART)

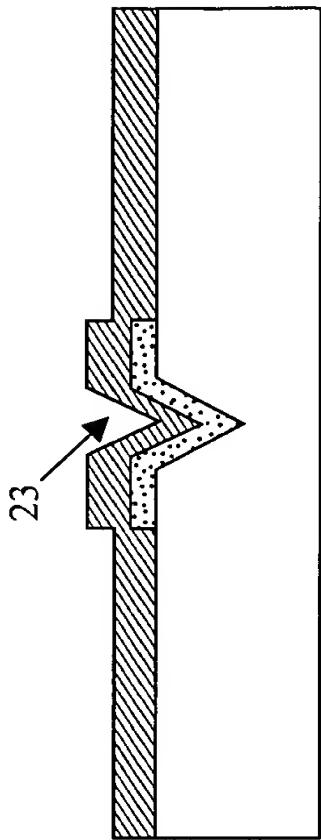
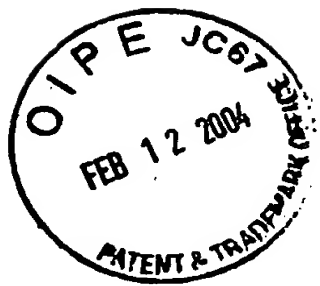


FIG. 2A
(PRIOR ART)

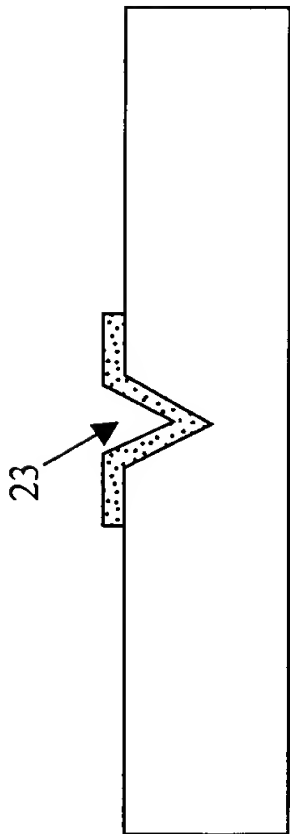


FIG. 2B
(PRIOR ART)

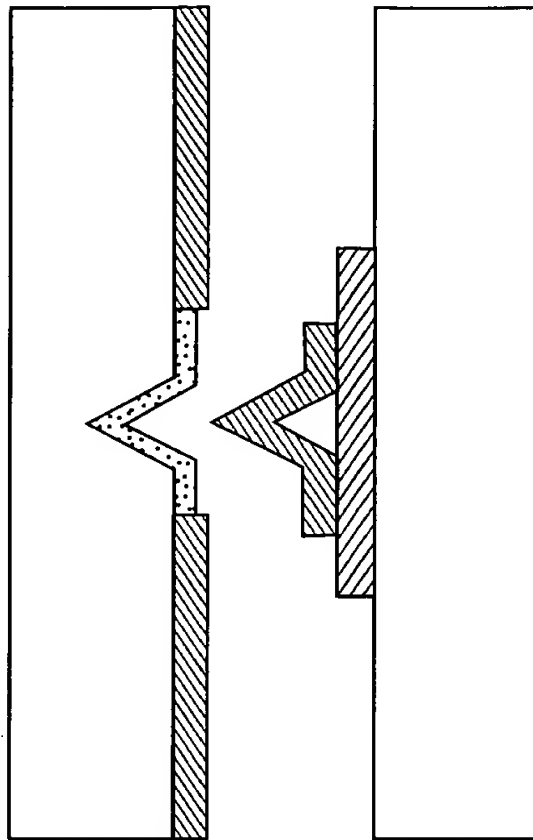


FIG. 2C
(PRIOR ART)

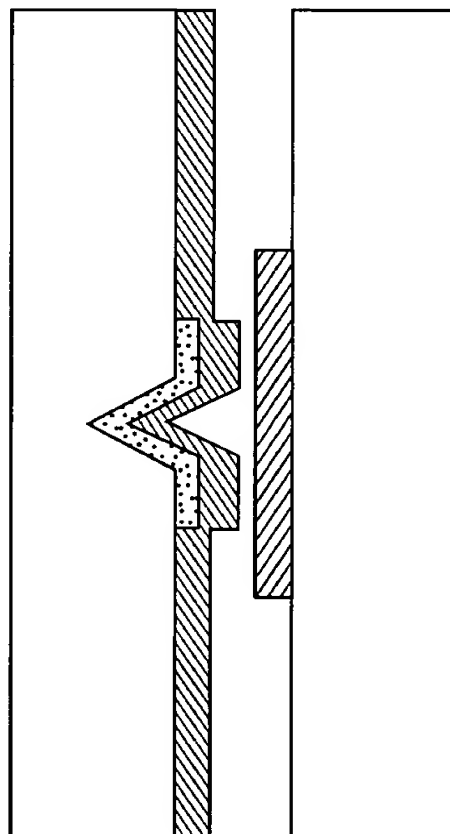


FIG. 2D
(PRIOR ART)

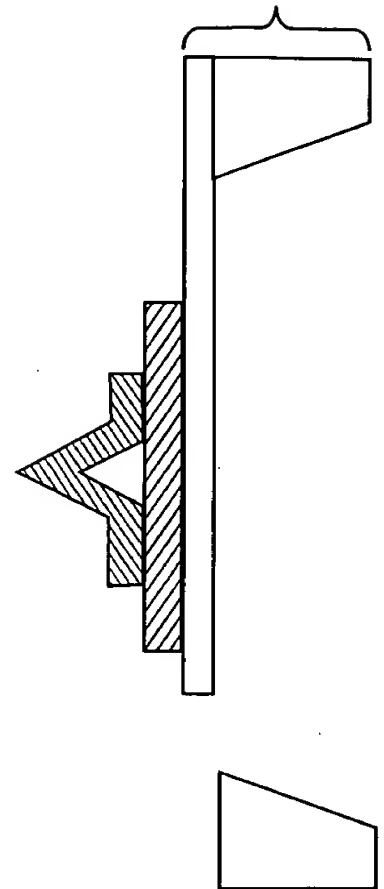


FIG. 2E
(PRIOR ART)

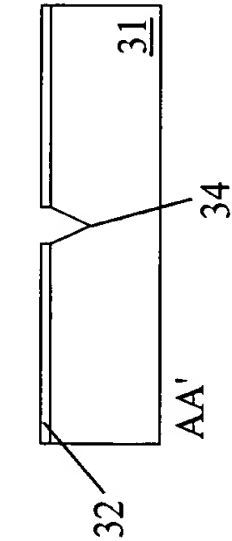
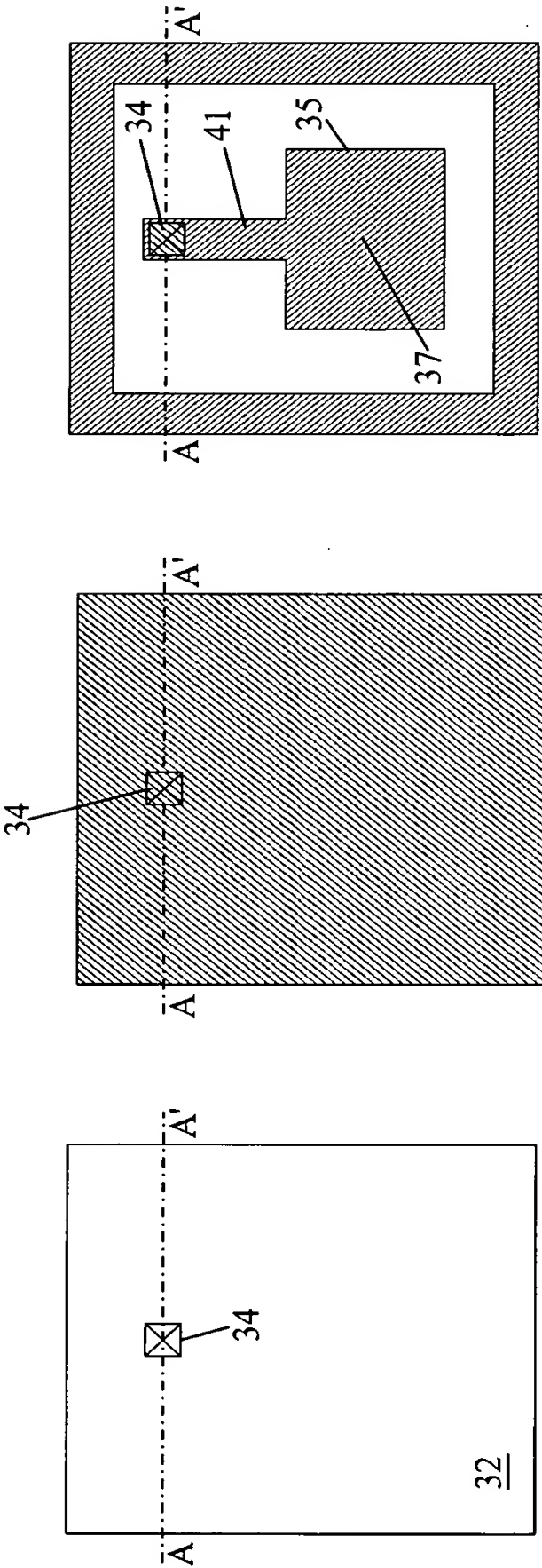
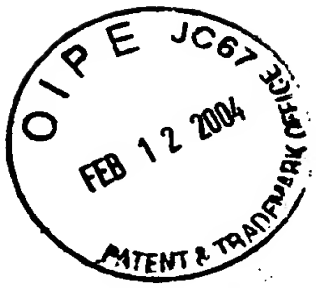


FIG. 3A

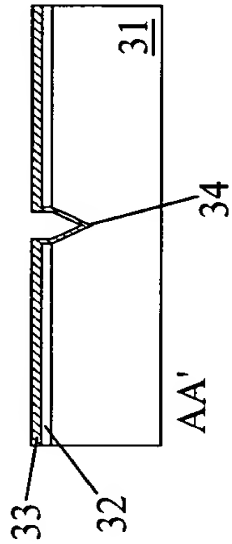
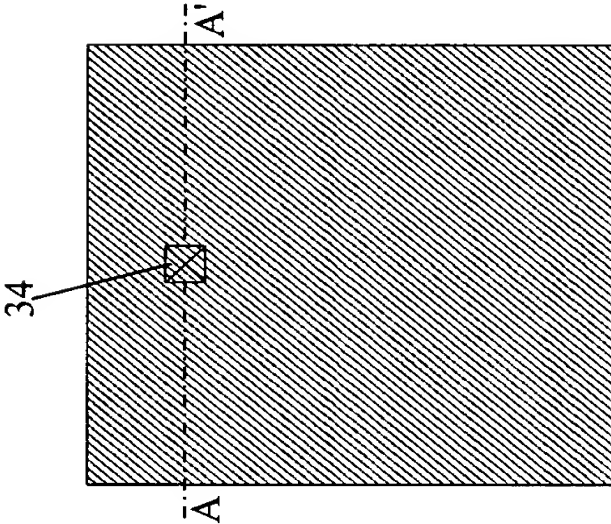


FIG. 3B

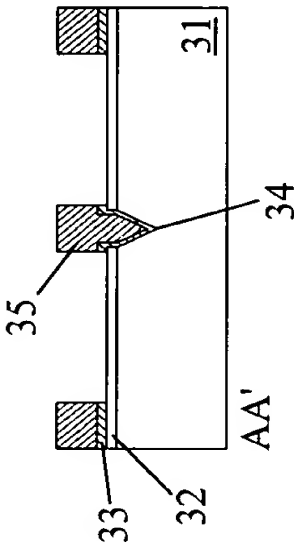
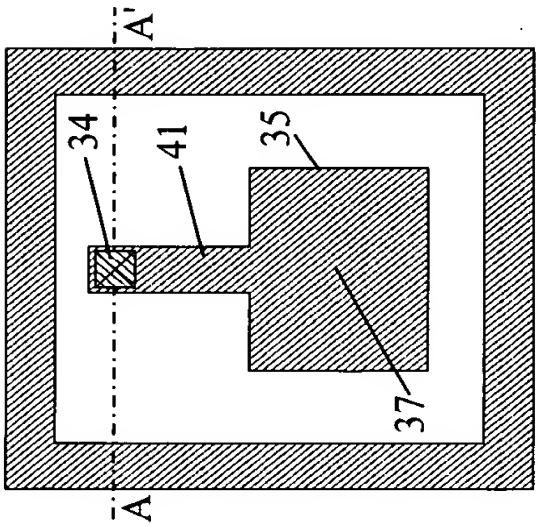
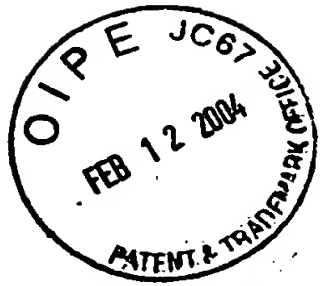


FIG. 3C



PROBE TIP AND METHOD OF MANUFACTURING PROBE TIPS BY PEEL-OFF

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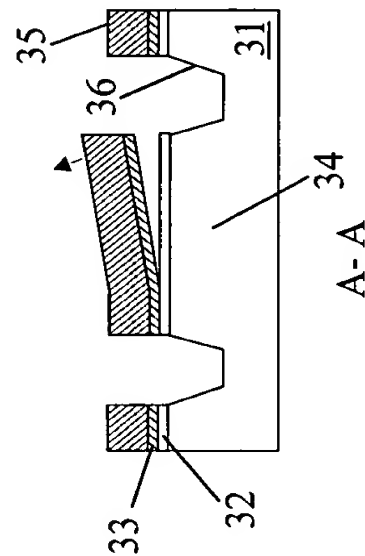
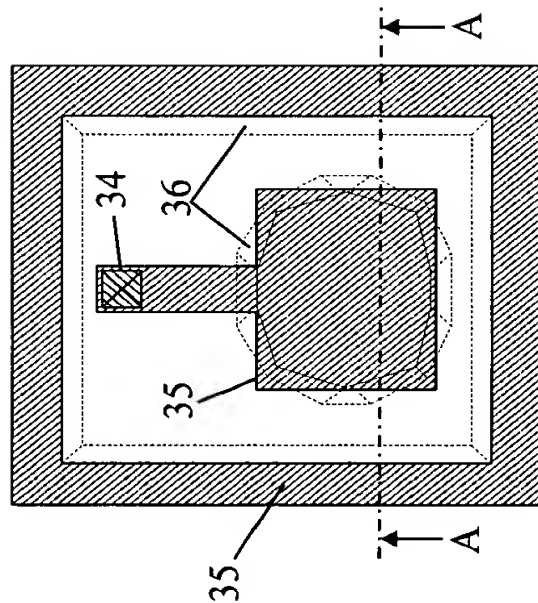


FIG. 3D

FIG. 3E

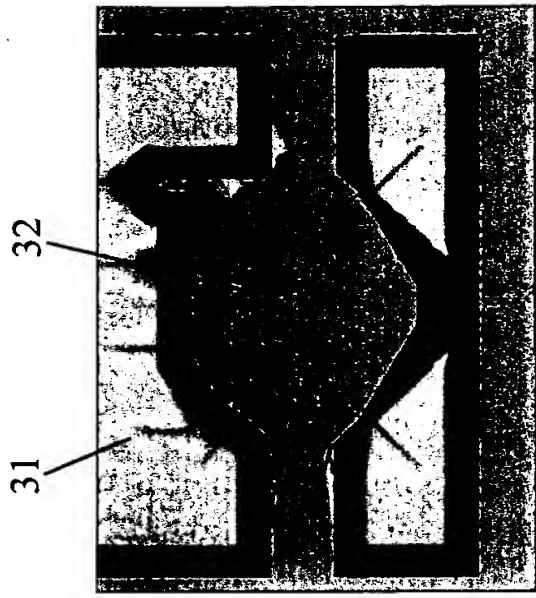


FIG. 4C

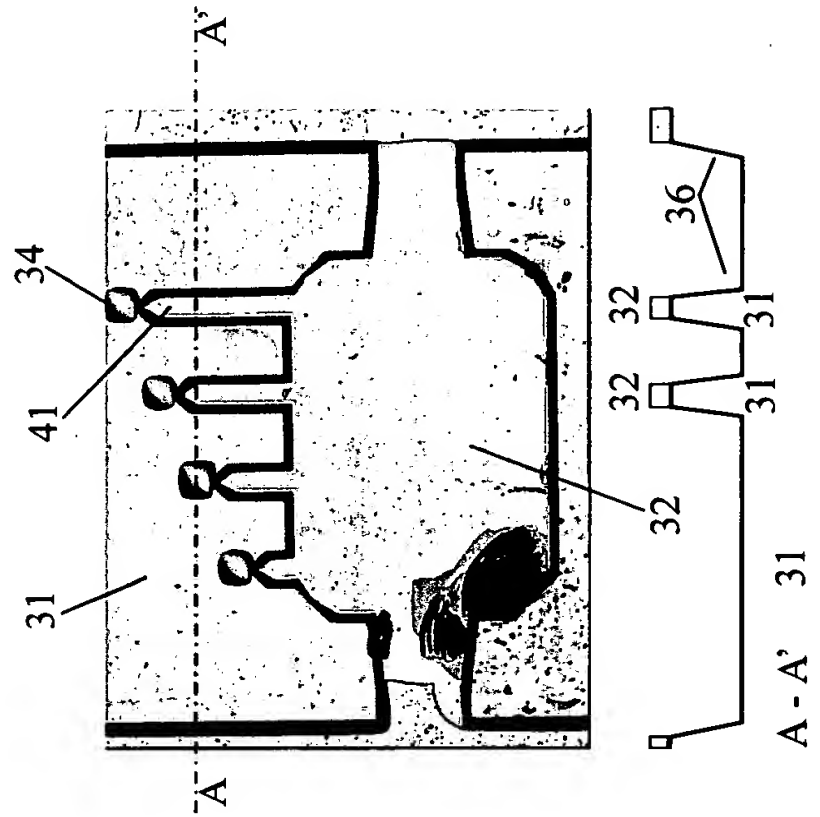


FIG. 4E

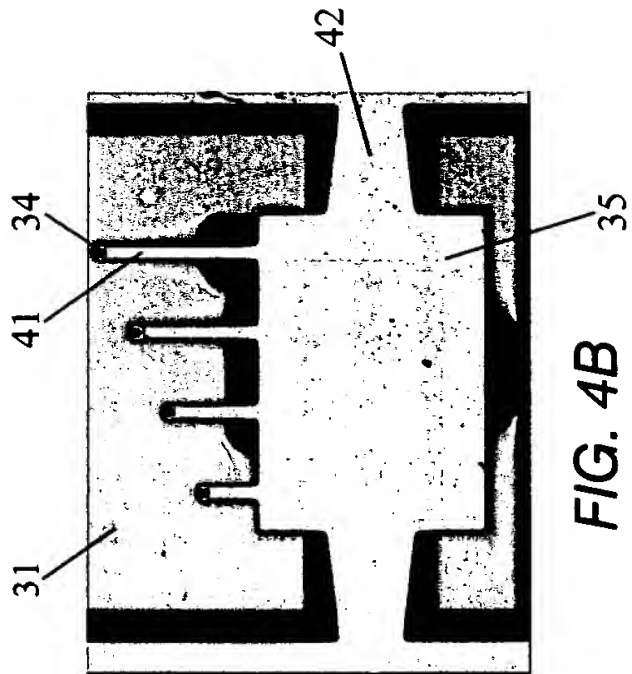


FIG. 4B

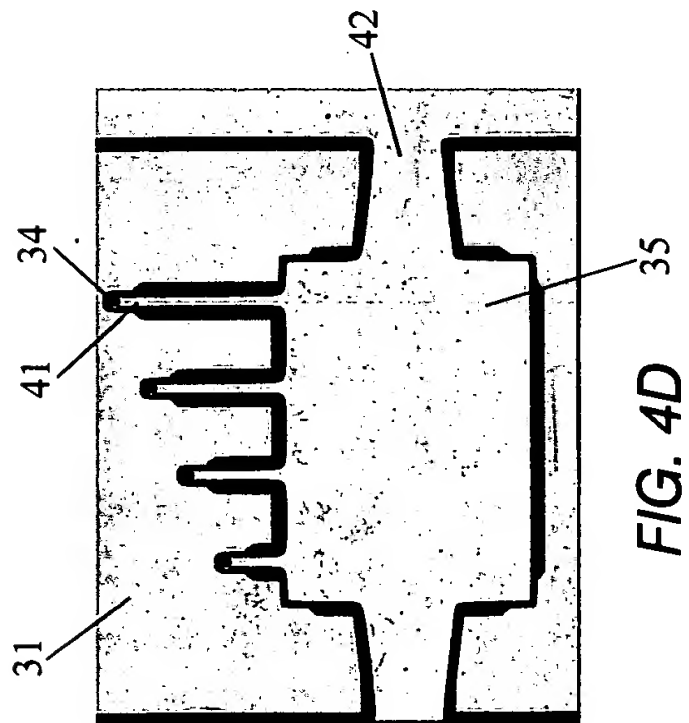


FIG. 4D

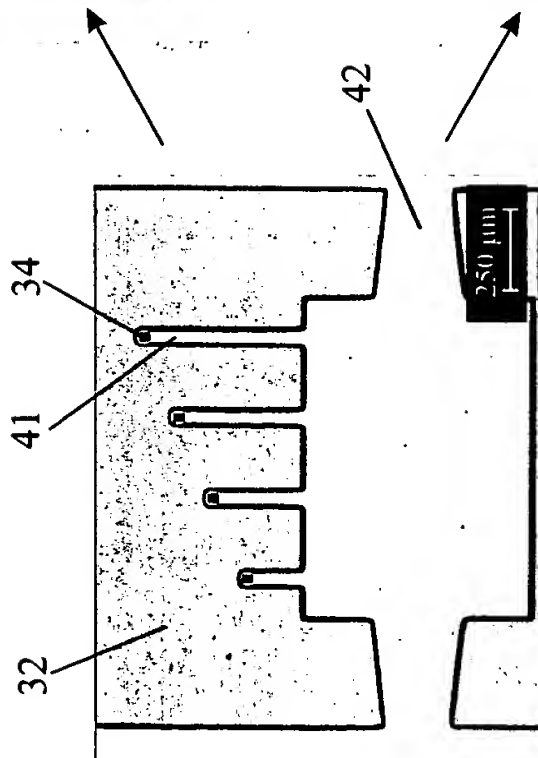


FIG. 4A

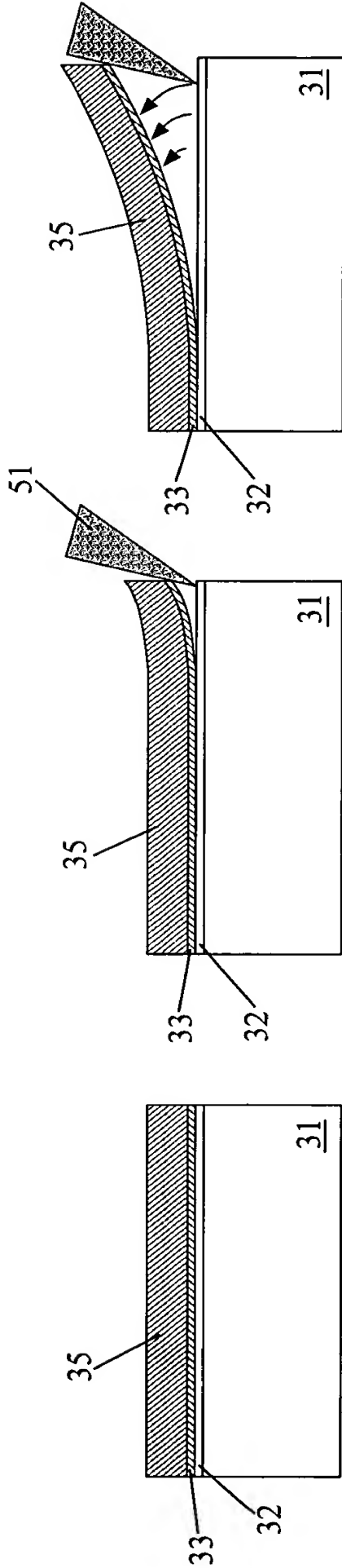


FIG. 5A

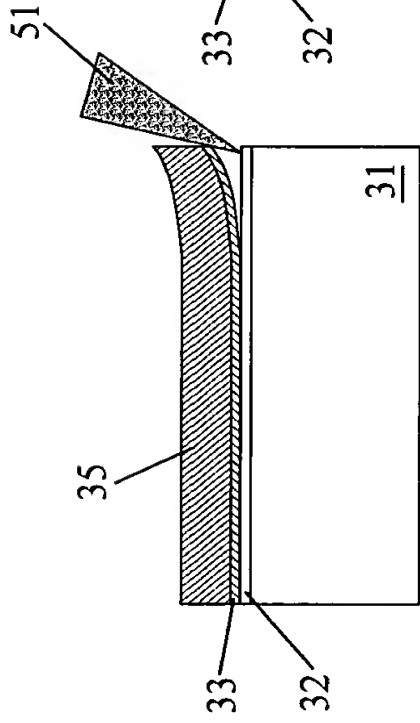


FIG. 5B

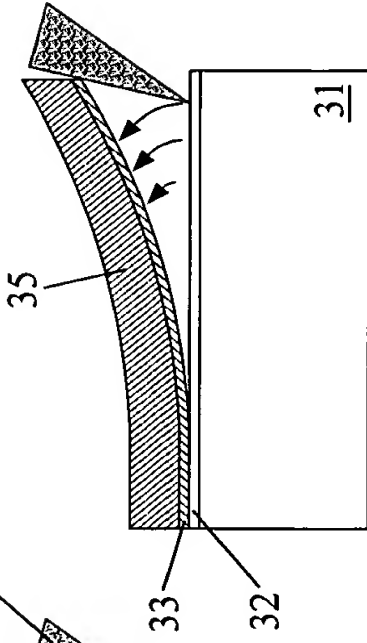


FIG. 5C

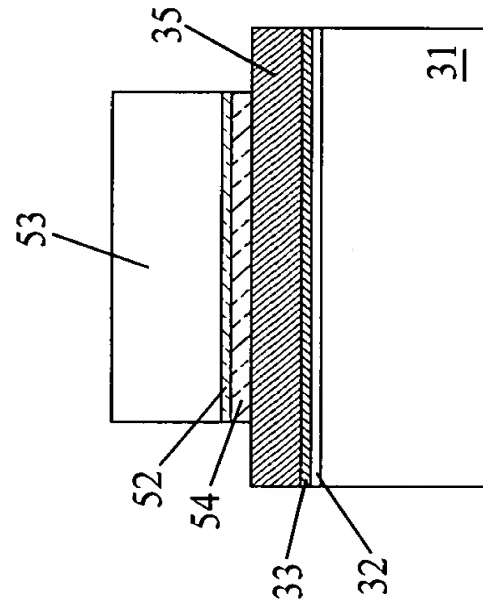


FIG. 5D

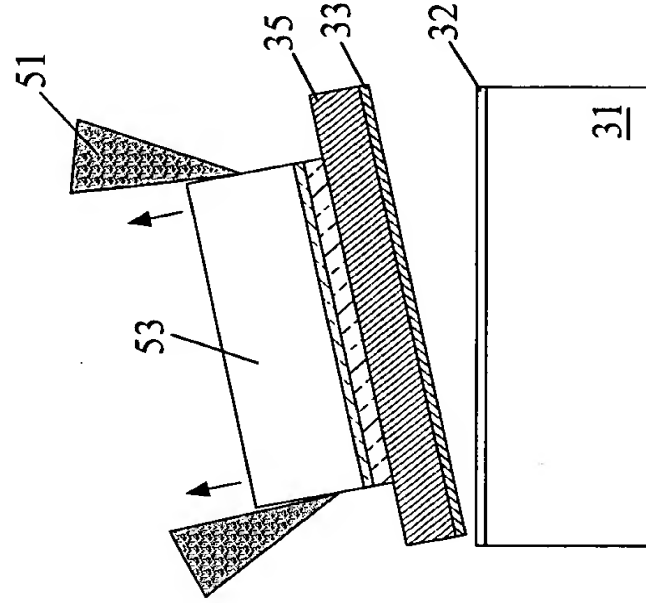


FIG. 5E

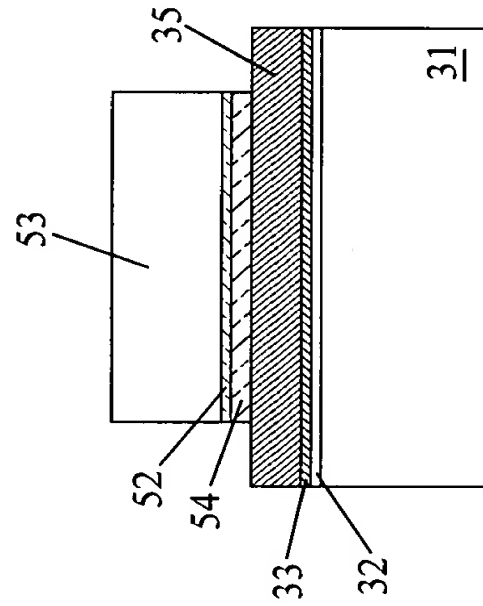


FIG. 5F

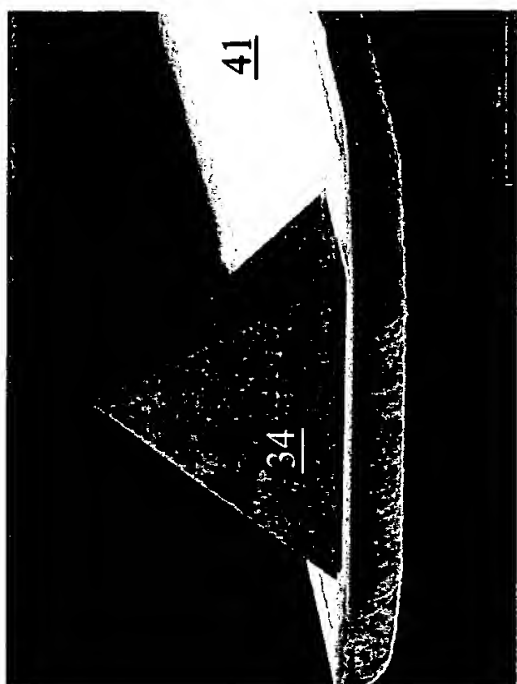


FIG. 6B

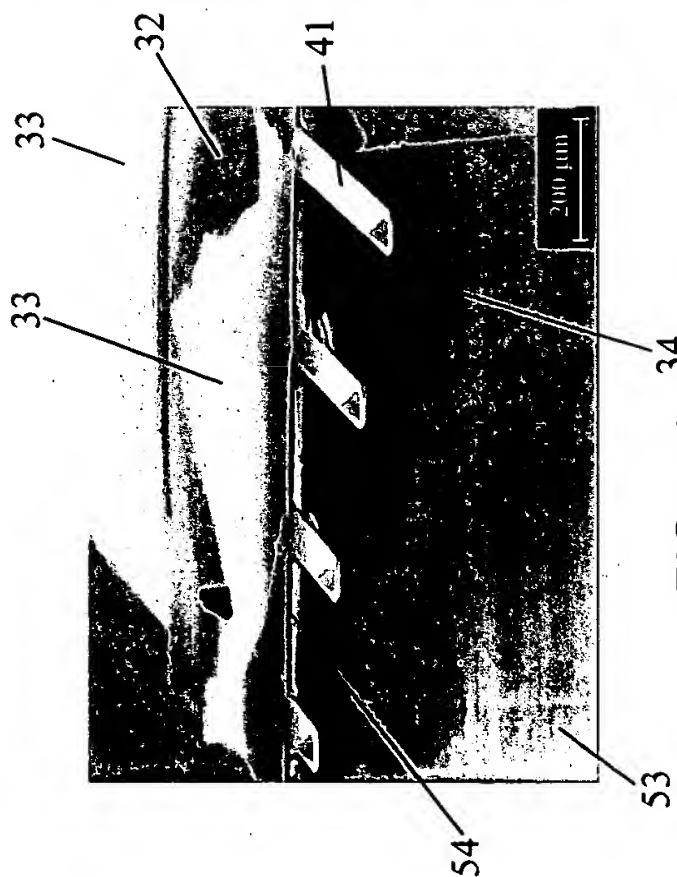


FIG. 6A

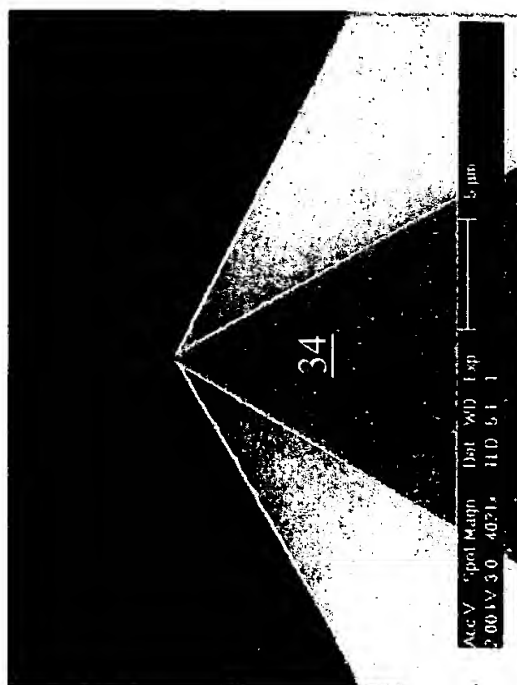


FIG. 6C

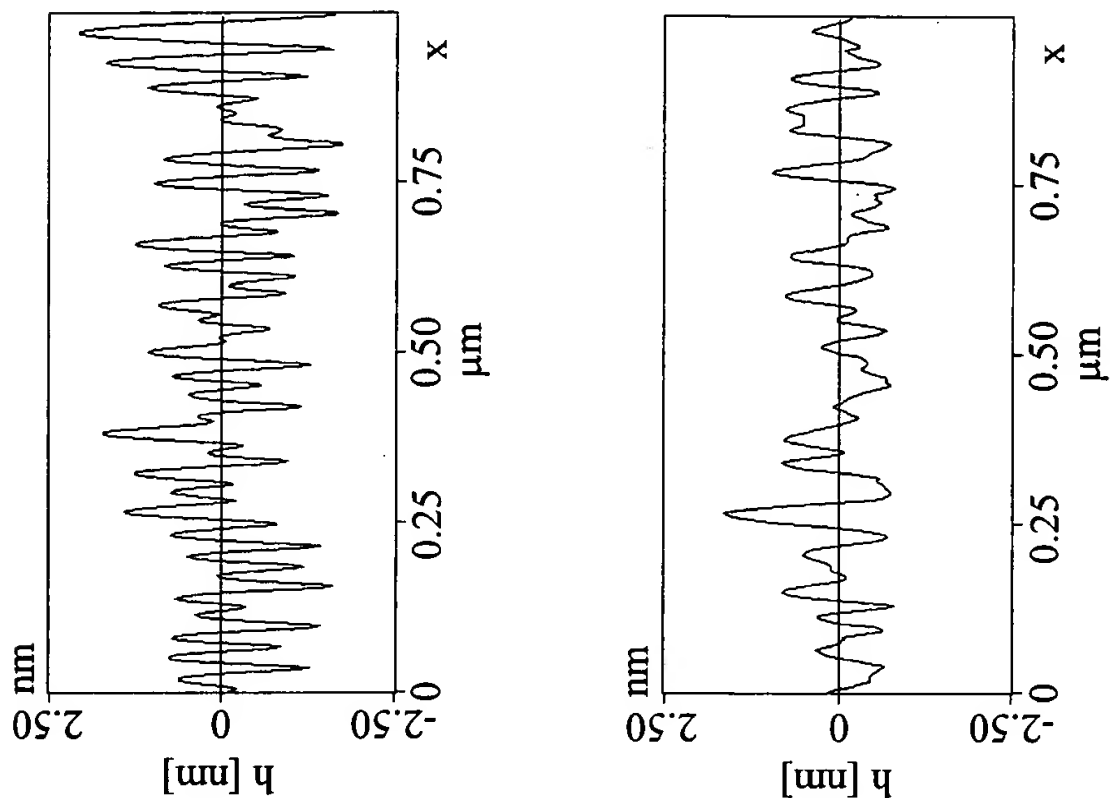


FIG. 7A

FIG. 7B

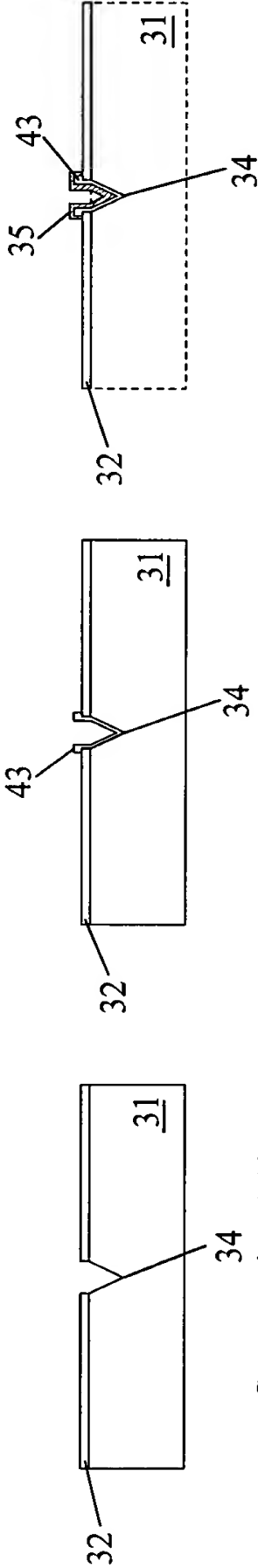
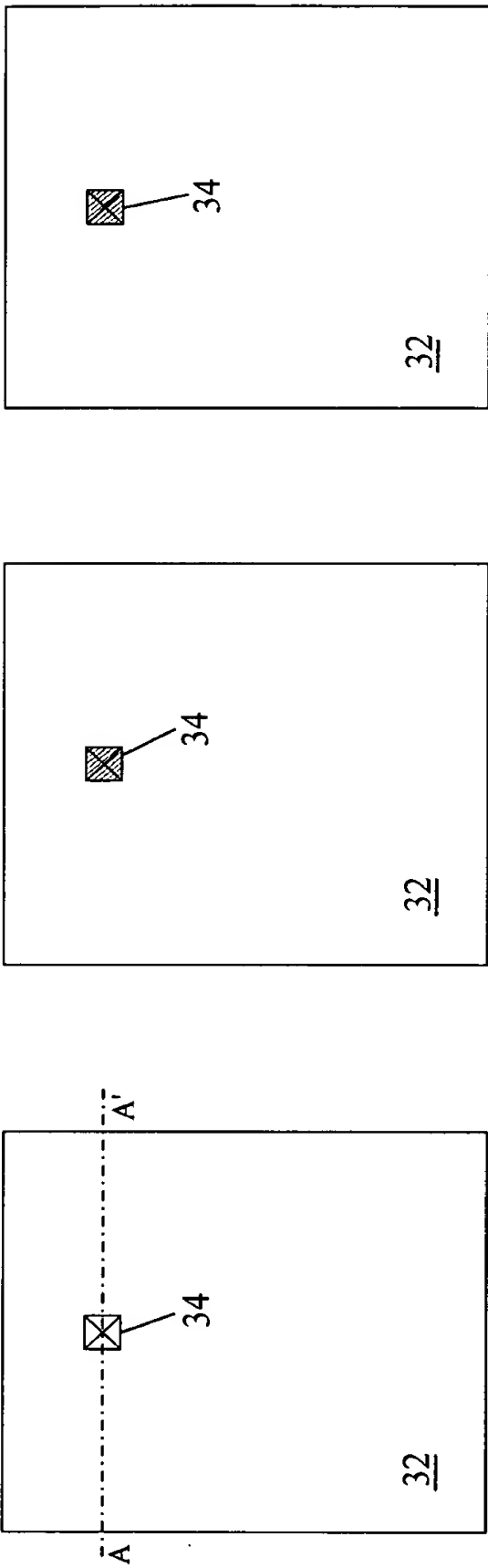
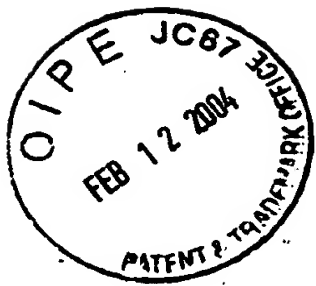


FIG. 8A

FIG. 8B

FIG. 8C

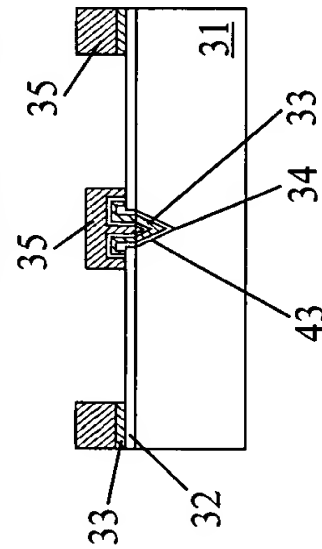
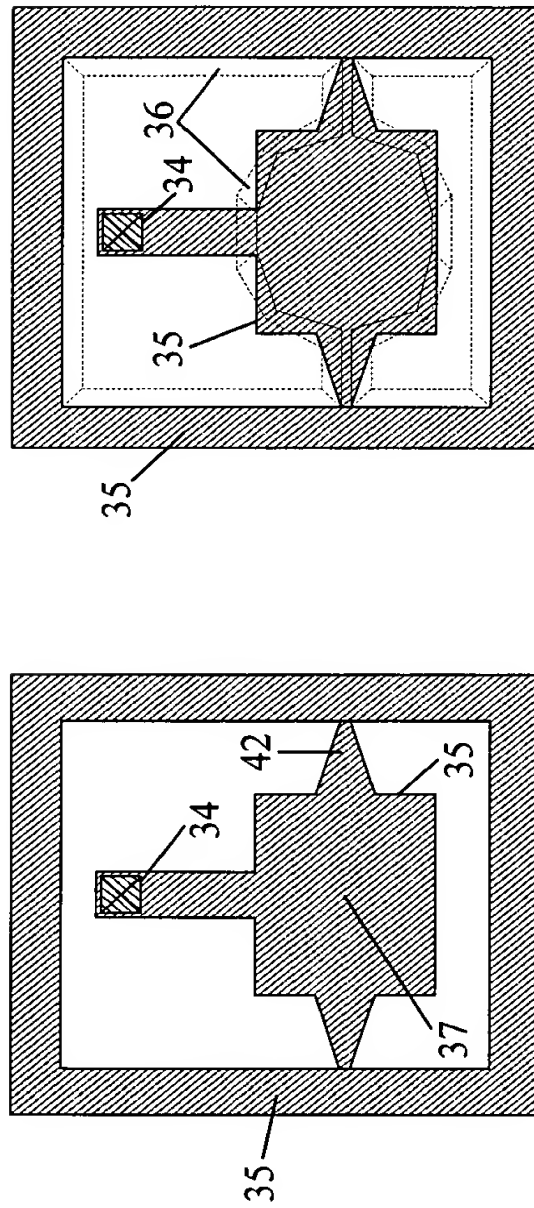
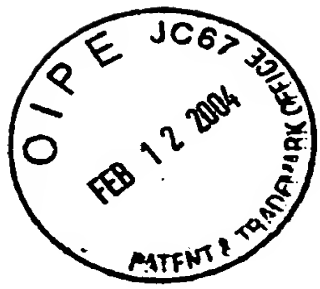


FIG. 8D

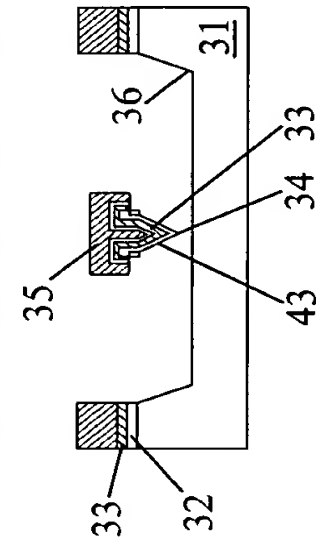
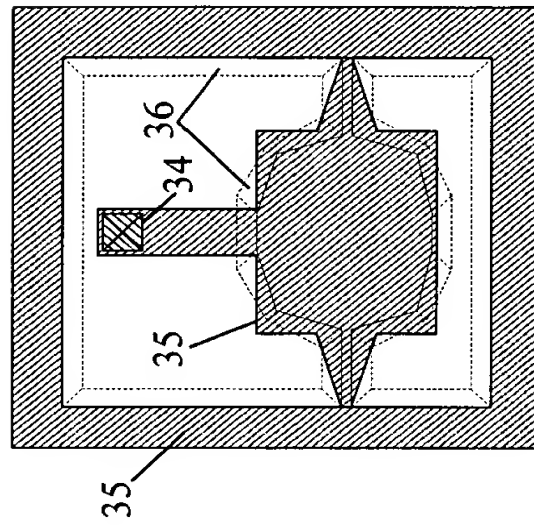


FIG. 8E



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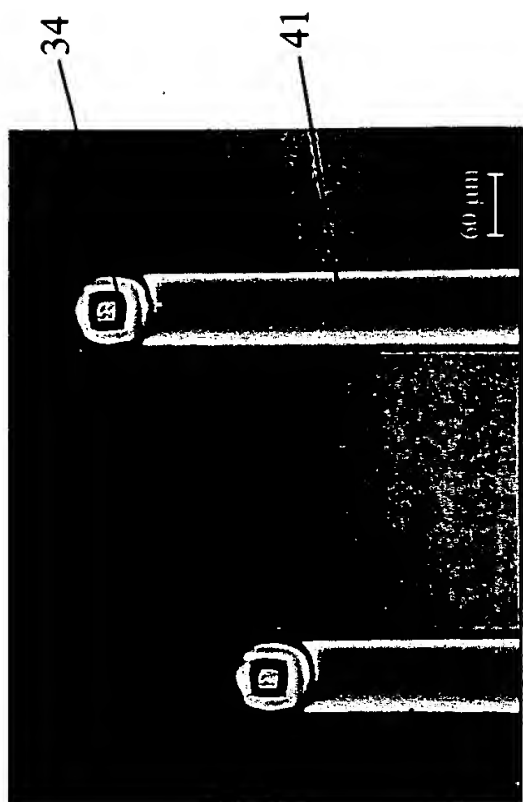


FIG. 9B

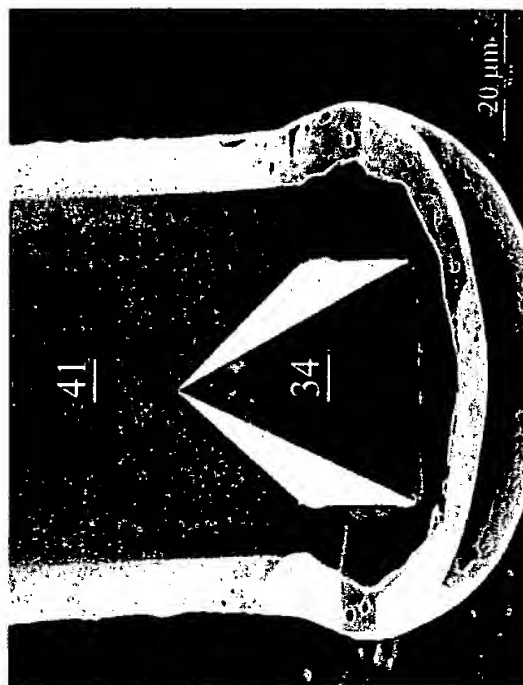


FIG. 9D

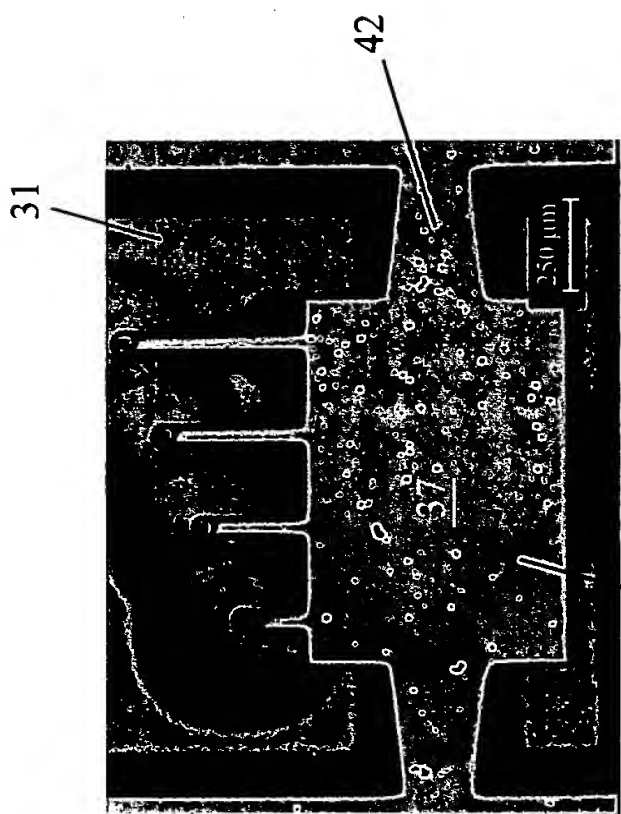
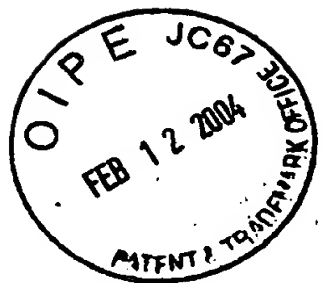


FIG. 9A



FIG. 9C



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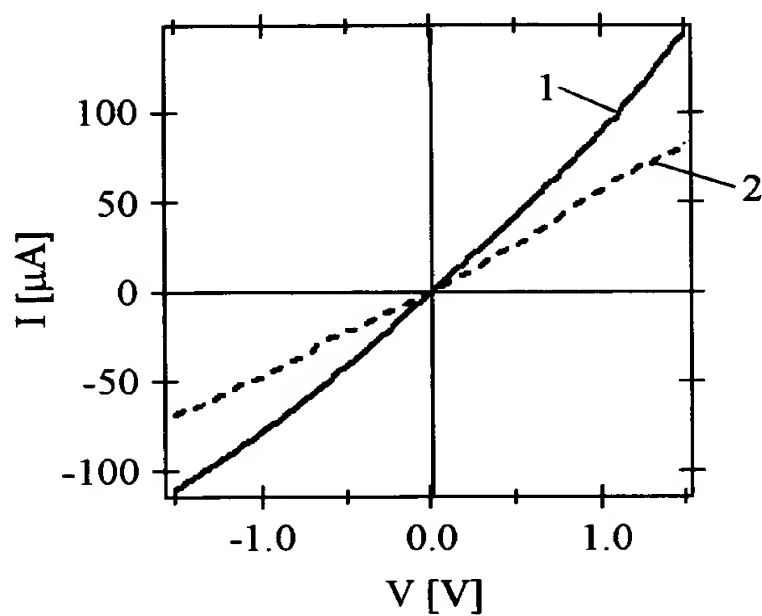


FIG. 10A

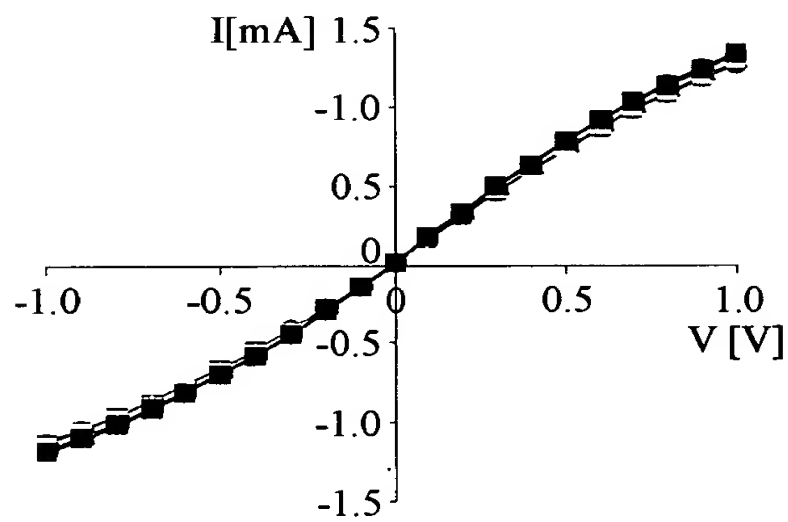


FIG. 10B

FIG. 11A

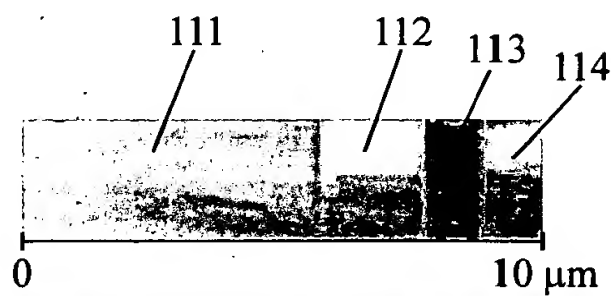


FIG. 11B



FIG. 11C

